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FORM PTO 14			,	АТТ	ATTY DOCKET NO. APPLICATION NO. / FASSIGNED & C				
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				<u></u>	02299.002230.		APPLICATION NOT APPLICATION NOT YET ASSIGNED 6 (a 35 U.S.C. 371 of PCT/EP2004/051843)		
				APP	MARINUS VAN DEN ELZEN, ET AL.				
					FILING DATE Concurrently herewith		GROUP N.Y.A.		
	 		·	U.S. P	PATENT DOCUMENTS				
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE		NAME	CLASS	S SUBCLASS	FILING DATE IF APPROPRIATE	
/JP/		3,353,329	11/21/6	57	CLOUD, ET AL.	53	30		
		4,034,536	7/12/77	7	MAHAFFY, ET AL.	53	22		
		4,154,636	5/15/79	9	MOTOYAMA, ET AL.	156	243		
<u>V</u>		4,506,495	3/26/85	5	ROMAGNOLI	53	559		
/JP/		4,604,852	8/12/86	6	BECKER	53	444		
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			F0	IREIGN	N PATENT DOCUMENTS			· · · · · ·	
		DOCUMENT NUMBER	DATE		COUNTRY	CLASS	S SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT-	
/JP/	СН	421 801	9/30/66	5	Switzerland		·	Abstract	
/JP/	GB	1 297 000	11/22/72	2	United Kingdom				
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	г	ОТНЕ	R DOCUMENT(S)) (Inclu	uding Author, Title, Date, Pertinent Pages, Etc.)		· · ·		
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EXAMINER	/John F	Paradiso/ (10/01/200	J 7)		DATE CONSIDERED 10/01/2007				

Sheet_1_ of _1_

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.